

LCR-8200(A) Series

High Frequency LCR Meter

FEATURES

- Wide Test Frequency : LCR-8200A : DC, 10Hz ~ 50/30/20/10/5 MHz LCR-8200 : DC, 10Hz ~ 30/20/10/5/1 MHz
- 7" LCD color Display
- 0.08% Basic Accuracy
- Displaying Four Measurement Results Simultaneously From 17 Selectable Measurement Parameters Freely
- 15 Steps List Measurement
- Two Curves Sweep Mode
- Equivalent Circuit Model Analysis (LCR-8200A only)
- Internal DC Bias Voltage ±12V
- USB Storage Available
- ALC Function Available
- Standard Interfaces : RS-232C, USB Host/Device, LAN, GPIB and Handler
- Universal Power Input

GW Instek's high-frequency LCR tester ~ LCR-8200 (A), which includes two series, LCR-8200A and LCR-8200, has ten models and the maximum test frequency is up to 50MHz. The entire series adopts 7-inch color display and features a high measurement accuracy (0.08%). The measurement results can be presented numerically or graphically according to the selected measurement mode, allowing users to optimally interpret the characteristics of the DUT. At the same time, a full range of standard interfaces such as USB device / RS-232C / Handler and GPIB allow users to control the instrument by the most familiar interface without worrying about additional hardware investment costs. Furthermore, the series also provides USB storage function when operating in the graphics mode. The measured characteristic curves and values of the DUT are saved for subsequent analysis. The wide variety of features of the LCR-8200 (A) can help users easily respond to the test requirements of passive components in R&D, engineering, and production.

Under the numerical measurement mode, it is divided into MEAS measurement and LIST measurement. Under the MEAS measurement mode, users can select up to 4 (at least 1) desired measurement items from the 17 measurement parameters. Each selected measurement item can be set to compare (PASS/FAIL judgement) or to the BIN function to conduct judgement and sorting, so that users can easily learn the results of the measurement by color and sound. Under the LIST mode, users is allowed to set 15 test points and each test point can set parameters independently, including frequency/voltage/bias, and it even can set independent comparison function and numerical display mode (value, difference value, difference percentage). On top of that, under the LIST mode, the automatic trigger mode is also provided. After each LIST measurement is completed, the instrument will be in the mechanism of standby trigger. Users only need to place the next DUT, and the LIST test can be automatically performed that saves time of repeatedly pressing the trigger button.

Under the graphical measurement mode, the SWEEP measurement provides the ability to sweep two parameters simultaneously (TRACE A / TRACE B). The relative parameters of the sweep, including the sweep source (frequency, voltage, current or bias voltage), horizontal / vertical axis scale (LINEAR / LOG), speed...etc., even adding a bias, can be set and tested according to the actual needs of users. Besides, the LCR-8200A series provides 7 different equivalent circuit models which allows user analysis by 3-components or 4-components combination to characterize the operational characteristics of the circuit. After the sweep is completed, the scale can be automatically adjusted according to the selected TRACE, so that the whole observation is clearer and easier to read. Other than that, the sweep traphics (bmp) and values (csv) can be saved to the flash drive for subsequent analysis and applications.

Whether it is for measurement data collection during the test process or the collocation for the system integration, the LCR-8200 (A) series offers the most comprehensive communications interfaces, including USB device, RS-232C, LAN for PC connection and even GPIB, which are all standard communications interfaces. Users can choose according to the habits of use and the convenience of the system architecture without any additional cost. In addition, the LCR-8200 (A) series also provides a Handler interface for system integration of PLCs or sorters.



PANEL INTRODUCTION

A. THE PRESENTATION OF FLEXIBLE MEASUREMENT COMBINATIONS

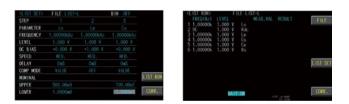


LCR-8200(A) Series allows users to select and arrange measurement parameters. Users can select at least one parameter to maximum four parameters from the 17 measurement parameters according to the measurement requirements and the presentation order can also be arranged in a desired manner. The set parameters can be stored in internal/external memory groups for subsequent recalls.

LIST MEASUREMENT

BIN FUNCTION

F



The 15-point LIST measurement mode provides measurement values at a specific frequency or voltage of the DUT, and each set point can set independent comparison and judgement. When the trigger mode is set to "AUTO", the display "WAIT ON" will appear on the measurement screen and LCR-8200(A) Series will detect the contact status of the fixture. When the DUT is connected, the test will start automatically.

Meass Display FILE Reliability Ls -26.013 k H Description Q 2.91 Rs 56.080 MΩ Rs 56.080 MΩ Rs 0.052 kGal 0.000 kGal Rs 30.952 MΩ 0.000 kGal 0.000 kGal 0.000 kGal 0.000 kGal Rs 1.0000 kGal SPEED FASI 0.000 kGal 0.000 kGal 0.000 kGal FRed 1.0000 kGal SPEED FASI TRIG REPEAL 0.000 kGal 0.000 kGal Rode FMED RATIO SPEED FASI COM MGAL 0.000 kGal 0.000 kGal Rode FMED RATIO SPEED FASI TRIG REPEAL 0.000 kGal 0.000 kGal Rode FMED RATIO SPEED FASI RAGE RUID mark 0.000 kGal 0.000 kGal Rode FMED RATIO SPEED FASI KIR 0.000 kGal 0.000 kGal Rode FMED RATIO SPEED FASI RAGE RUID mark 0.000 kGal 0.000 kGal 0.000 kGal

INDEPENDENT SETTING JUDGMENT

Each selected test parameter can independently set judgement and comparison such as value, difference value or difference percentage. Additionally, the display method can also be based on value, difference value or difference percentage to self-define the presentation of test results, and the observation is more in line with the actual needs. In addition to using the warning sound, all the parameters set for comparison judgment will be displayed in different colors. "Red" means that the limit value is exceeded, and "Green" means that it is within the limit value, so that the judgment can be conducted smoothly under noisy environment.

D. TWO-CURVE SWEEP

Β.



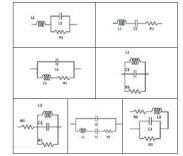
Up to 2 characteristic parameters of the DUT can be swept at the same time. Sweep type (frequency/Vac/Iac), axis form (LOG/LINEAR), sweep speed, even adding bias (internal), etc can be set according to the actual demands. After the sweep is completed, automatic adjustment can be used to obtain the best observation display. The movable cursor can be used to obtain the measurement result of the specific position. Swept displays and point values can be saved to the flash drive via the USB host on the panel for subsequent analysis.

F. EQUIVALENT CIRCUIT MODEL ANALYSIS



BIN settings for one specific parameter of the selected measurement parameters provide up to 9 BIN positions. Set the judgment basis for individual classifications according to the desired BIN methods (EQUAL/SEQUENTIAL/TOLERANCE/RANDOM) and limit value mode (VALUE/delta/delta%). The result of this sorting can be obtained through the Handler interface. If directly connected to an external device such as a sorter, an immediate sorting can be performed.





This function, which adopts the algorithm based on resonance theory, consists of 7 different equivalent circuit models. The 3-components analysis model is composed of 4 types, A, B, C and D, whereas the 4-components analysis model covers 3 types, E, F and G. By selecting suitable equivalent circuit model, the instrument will automatically calculate approximate value of each component parameter after measurement, and generate simulated curve (TRACE A/B SIMULATION) to compare with the measured curve (TRACE A/B).

Also, it's available to choose equivalent circuit model followed by directly input value of each component parameter to generate a simulated curve (TRACE A/B SIMULATION) to further compare with the measured curve (TRACE A/B). The parameters of both resonance frequency (SRF) and quality factor (Qm) can be displayed simultaneously.

SPECIFICATION	IS					
	LCR-8250A	LCR-8230A	LCR-8220A	LCR-8210A	LCR-8205A	-
	-	LCR-8230	LCR-8220	LCR-8210	LCR-8205	LCR-8201
TEST FREQUENCY					1	
	DC, 10Hz~50MHz;	DC, 10Hz~30MHz;	DC, 10Hz~20MHz;	DC, 10Hz~10MHz;	DC, 10Hz~5MHz;	DC, 10Hz~1MHz;
	6 Digits, ±0.0007%	6 Digits, ±0.0007%	6 Digits, ±0.0007%	6 Digits, ±0.0007%	6 Digits, ±0.0007%	6 Digits, ±0.0007%
OUTPUT IMPEDANCE	1					
	25Ω / 100Ω SELECTA	BLE				
BASIC ACCURACY						
	±0.08%					
TEST SPEED	MAX: 2 5mc(>10kHz)	EAST: 50mc (> 20H-) M	EDIUM: 100ms, SLOW:	200mc SLOVY/2: 600mc		
TEST SIGNAL LEVEL	[WAX. 2. JIII3(>TOKI12)	, 1A31. Johns (>20112), M	EDIOWI. TOOTIS, SEOW.	500ms, 5E0 w2. 000ms		
AC Voltage	10mV ~ 2Vrms (FREQ	≦1MHz), 10mV ~ 1Vrn	ns (FREQ. > 1MHz or FR	EQ. ≦1MHz and RO=25	Ω)	
AC Current	100 μ A ~ 20mArms (RO=100 Ω), 200 μ A ~ 40mArms (RO=25 Ω)					
DCR Voltage	1Vdc (40mA max.)					
MEASUREMENT PARAME	1					
				time Impedance (Z), Ind		
	Susceptance (B), DC F		ssipation Factor (D), Adr	nittance (Y), Conductanc	e (G), Reactance (X), Ph	ase Angle (b d / b r),
LIST MEASUREMENT	Jusceptance (b), DC I					
Listed Steps	15					
Listed Parameters	Freq/Vac/Iac/DC Bias/Comp/BIN					
Trigger	AUTO, REPEAT, SINGLE					
SWEEP MEASUREMENT	1					
Swept Graphical	Two of measurement					
Swept Parameters	Freq/Vac/Iac/BIAS V, I	Keep Trace				
EQUIVALENT CIRCUIT MC						
	7 different equivalent	circuit models, 3-compo	nents, 4 types, 4-compo	nents, 3 types		
OTHER FUNCTIONS	1					
Auto Level Control (ALC)	Standard					
DC Bias	0 ~ ±12V PASS, FAIL and OK, NG or BIN 1-9					
Handler	PASS, FAIL and OK, N	G or BIN 1-9				
OTHER FEATURES						
Correction V/I Monitor	Open/Short/HF Load Vac, Iac, Vdc, Idc	/Load				
Comparator	Value, Δ , Δ %					
Buzzer	OFF, Pass, Fail					
Average	1 to 64					
DISPLAY						
	7" LCD color display (8	300 x 480)				
INTERFACE	LISB/CPIB/LAN/RS-23	2/Handler/USB Host/TI	RICCER Input			
POWER SOURCE		2/11/01/01/03/01/03/01				
	AC 100V~240V, 50/60	Hz; Consumption: 65VA	(max.)			
DIMENSIONS & WEIGHT						
		5 (D) mm; Approx. 3.3kg	,,			
Difference between "A" series and	"Non-A" series is only the "A" s			Specifications	subject to change without r	notice. LCR-8000ACD1
ORDERING INFORM	ATION		CESSORIES	en Candu 1. Test Elstern 1.05	OCD w 1 Cafety Charts 1	
	50MHz High Frequency	LCR Meter		er Cord x 1, Test Fixture LCF	к-овых I, Safety Sheet x 1	
	30MHz High Frequency	LCR Meter	TION 2054 Test Eixture for Avis	& Padial Load Come	inte ICR-154 Test E	ixture for SMD/Chip
	20MHz High Frequency		(up to 50MHz)	al & Radial Lead Compone		onents (up to 50MHz)
	10MHz High Frequency 5MHz High Frequency L	CD Mater	-06B Test Lead with Kelvi		GTL-234 RS-232	2C cable
	30MHz High Frequency	CD Mater	R-07 Test Lead with Allig	ator clip(2 wire type) s) for SMD/Chip Compon	GTL-248 GPIB (ents GTL-246 USB C	
	20MHz High Frequency		-108 Test Fixture(Tweezer -10A Test Fixture for Botto			adie al DC Bias Voltage Box
LCR-8210 DC, 10Hz~1	10MHz High Frequency	LCR Meter	(up to 50MHz)			shage box
	5MHz High Frequency L		LCR-12 Test Lead with Kelvin clip(4 wire type) GRA-445 Rack Mount Kit, 19" 4U size			
LCR-8201 DC, 10Hz~1	1MHz High Frequency L	CK Meter	Nack WOUTH NIL, 19	70 3120		





